## **Upadhyaya Awarded MRS-I Medal**

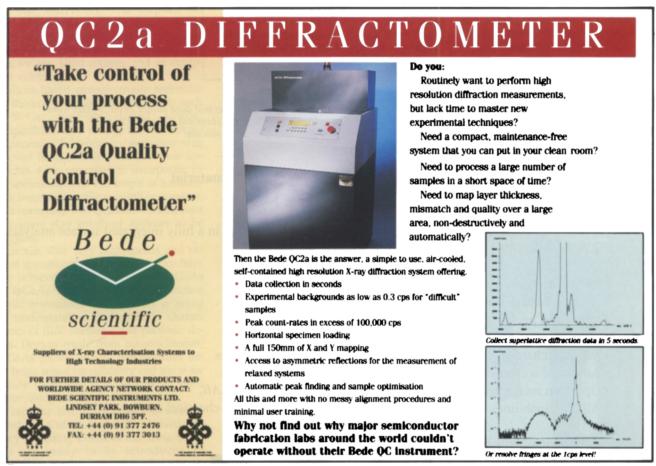
Gopal S. Upadhyaya, a professor since 1976 in the Department of Metallurgical Engineering at the Indian Institute of Technology (Kanpur), recently was awarded the 1993 MRS-I (Materials Research Society of India) Medal in recognition of his excellence in the field of sintering science and technology. Upadhyaya delivered the Medal Lecture, "Novel Sintered Cutting Tool Materials," based on the research of his team at the institute. In his talk, he elaborated on new findings related to high-speed steelbased composites containing refractory compound particles produced through liquid-phase sintering, and also on the

fundamental issues related to the binder substitution in WC-Co cemented carbides. These investigations have led to better tool lives.

Upadhyaya was president of the Powder Metallurgy Association of India for two consecutive terms. He has authored or co-authored more than 200 papers and six books. His latest book, Powder Processing of High  $T_c$  Oxide Superconductors and Their Properties (1992), is published by Trans Tech Publications Ltd., Switzerland (U.S. distributor: Ashgate Publishing Co., Old Post Road, Brookfield, VT 05036).

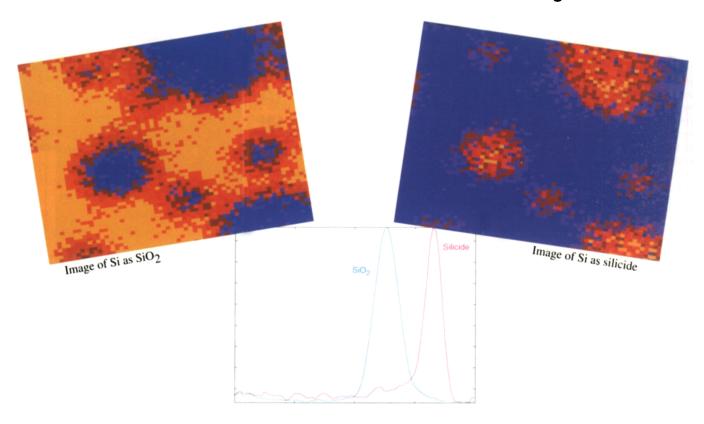


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